



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Abdullahman Sezginer et al.

Application No.: 10/613,378

Filed: July 3, 2003

For: OVERLAY METROLOGY METHOD  
AND APPARATUS USING MORE  
THAN ONE GRATING PER  
MEASUREMENT DIRECTION

Confirmation No.: 7200

Group Art Unit: 2877

Examiner: Gordon J. Stock, Jr.

**RESPONSE TO OFFICE ACTION  
MAILED APRIL 19, 2006**

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San Francisco, CA 94111  
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M/S AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited  
with the United States Postal Service as First Class Mail in an  
envelope, addressed to: Commissioner for Patents, P.O.  
Box 1450, Alexandria, VA 22313-1450 on June 21, 2006.

STALLMAN &amp; POLLOCK LLP

Dated: 06/21/2006

By:

  
Georgia K. Stith

Sir:

In response to the Office Action dated April 19, 2005, please amend the above-identified  
application as follows:

**Amendment to the Claims** are reflected in the listing of claims which begins on page 2 of this  
paper.

**Remarks** begin on page 4 of this paper.